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DIFFORMATION DISCLOSURE STATEMENT

IN AN APPLICATION

(Use several sheets if necessary)

Sheet 1 of 1

Docket Number:
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Applicante MIYAZAKI et al.

Filing Date: **CONCORRENT**

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Group Art Unit: **Dresser**

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| EXAMINER INITIAL | DOCUMENT NO. | DATE | NAME | CLASS | SUBCLASS | | DATE OPRIATE |
| | NONE | | | | | | |
| | | FOR | EIGN PATENT DOCUM | MENTS | | | |
| | DOCUMENT NO. | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
| | <u> </u> | | | | | YES | NO |
| | 2002-119623 | 23.04.03 | JANYAN | | | | |
| | NONE | | | | | | |
| | OTHER | DOCUMENTS | (Including Author, Title, | Date, Pertinent I | ages, Etc.) | | <u> </u> |
| | Applie Vol.87 | d Physics | tron microscope, , 15 May, 2000 pages 7152 to 71 | Journal (15 05 00) | | | |
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| | 1 15 Ju | ly, 2002 (1209 to 1 | 15.07.02), Vol. | 27, No.14, | | | • |
| | Ridek | i T. HIYA | AKI et al., Lig | ht diffra | ction | | ······································ |
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| EXAMINER | /Arnel C. Lavarias/ | DATE CONSIDERED | 09/24/2008 |
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EXAMINER: Initial if reference considered, whether or not citation is to conformance with MPEP 605; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.

*Substitute Disclosure Statement Form (PTO-1449)

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